

# United States Patent and Trademark Office

UNITED STATES DEPARTMENT OF COMMERCE United States Patent and Trademark Office Address: COMMISSIONER FOR PATENTS P.O. Box 1450 Alexandria, Virginia 22313-1450 www.usplo.gov

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/540,389	07/20/2005	Satoshi Takei	124418	2689
25944 7590 06/07/2007 OLIFF & BERRIDGE, PLC			EXAMINER	
P.O. BOX 19928			CHOI, LING SIU	
ALEXANDRIA, VA 22320			ART UNIT	PAPER NUMBER
·		•	1713	
			MAIL DATE	DELIVERY MODE
			06/07/2007	PAPER

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

	Application No.	Applicant(s)	
	10/540,389	TAKEI ET AL.	
Office Action Summary	Examiner	Art Unit	
·.	Ling-Siu Choi	1713	
The MAILING DATE of this communication ap Period for Reply	pears on the cover sheet w	ith the correspondence addres	SS
A SHORTENED STATUTORY PERIOD FOR REPL WHICHEVER IS LONGER, FROM THE MAILING D  - Extensions of time may be available under the provisions of 37 CFR 1. after SIX (6) MONTHS from the mailing date of this communication.  - If NO period for reply is specified above, the maximum statutory period  - Failure to reply within the set or extended period for reply will, by statut Any reply received by the Office later than three months after the mailin earned patent term adjustment. See 37 CFR 1.704(b).	NATE OF THIS COMMUN 136(a). In no event, however, may a will apply and will expire SIX (6) MO e, cause the application to become A	CATION. reply be timely filed  NTHS from the mailing date of this commu BANDONED (35 U.S.C. § 133).	
Status			
Responsive to communication(s) filed on 15 №     This action is <b>FINAL</b> . 2b) This     Since this application is in condition for allowed closed in accordance with the practice under the condition of the c	s action is non-final. ince except for formal ma	·	erits is
Disposition of Claims			
4) ☐ Claim(s) 1-12 is/are pending in the application 4a) Of the above claim(s) is/are withdra 5) ☐ Claim(s) is/are allowed. 6) ☐ Claim(s) 1-12 is/are rejected. 7) ☐ Claim(s) is/are objected to. 8) ☐ Claim(s) are subject to restriction and/or	wn from consideration.		
Application Papers			
9) ☐ The specification is objected to by the Examine 10) ☑ The drawing(s) filed on 23 June 2005 is/are: a Applicant may not request that any objection to the Replacement drawing sheet(s) including the correct 11) ☐ The oath or declaration is objected to by the Examine 11.	a)⊠ accepted or b)⊡ objo drawing(s) be held in abeya ction is required if the drawing	nce. See 37 CFR 1.85(a). g(s) is objected to. See 37 CFR 1.	
Priority under 35 U.S.C. § 119			
a) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of:  1. Certified copies of the priority document 2. Certified copies of the priority document 3. Copies of the certified copies of the priority application from the International Burea * See the attached detailed Office action for a list	ts have been received. ts have been received in a prity documents have been u (PCT Rule 17.2(a)).	Application No n received in this National Stag	ge
•			
Attachment(s)	A) 🗖 lateau!	Summany (DTO 442)	
<ol> <li>Notice of References Cited (PTO-892)</li> <li>Notice of Draftsperson's Patent Drawing Review (PTO-948)</li> <li>Information Disclosure Statement(s) (PTO/SB/08)</li> <li>Paper No(s)/Mail Date</li> </ol>	Paper No	Summary (PTO-413) (s)/Mail Date Informal Patent Application	

Application/Control Number: 10/540,389 Page 2

Art Unit: 1713

## **DETAILED ACTION**

1. This Office action is in response to the Amendment filed 03/15/2007. Claim 13 was canceled and claims 1-12 are now pending. In view of the Amendment, the objections were withdrawn and the rejections of claims 1-12 by Rutter et al. (EP 1 150 343 A2), Takei et al. (EP 1 315 045 A1), and Meador et al. (US 5,919,599) are maintained.

## Claim Analysis

## 2. Summary of Claim 1:

A gap fill material forming composition, wherein				
the composition is used in manufacture of semiconductor device, comprising				
coating a photoresist on a substrate having a hole with aspect ratio shown in				
height/diameter of 1 or more, and				
transferring an image to the substrate by use of lithography process				
the composition is used in a process in which the composition				
is coated on the of substrate and is contacted with an alkaline aqueous				
solution after baking, then the photoresist is coated				
the composition comprises a polymer having a hydroxy group or a carboxy group				
and a crosslinking agent				
a gap fill material layer manufactured by				
coating the gap fill material forming composition on a semiconductor				
substrate and baking it				
has a dissolution rate for an alkaline aqueous solution having a				
concentration of 0.1% to 20% ranging from 3 to 200 nm per second				

### Claim Rejections - 35 USC § 102

3. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless --

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- (e) the invention was described in a patent granted on an application for patent by another filed in the United States before the invention thereof by the applicant for patent, or on an international application by another who has fulfilled the requirements of paragraphs (1), (2), and (4) of section 371(c) of this title before the invention thereof by the applicant for patent.
- 4. Claims 1-2 and 4-13 rejected under 35 U.S.C. 102(b) as being anticipated by Rutter et al. (EP 1 150 343 A2).

Rutter et al. disclose a composition comprising one or more crosslinkable polymers having a weight average molecular weight of less than or equal to about 8,000, wherein the crosslinkable polymer comprises at least one hydroxyl group containing monomer, wherein the crosslinker includes di-, tri-, tetra, or higher multifunctional ethylenically unsaturated monomer; the hydoxy group containing monomer is aliphatic or aromatic, which is vinyl phenol, vinyl cresol, vinyl methoxy phenol, hydroxyethyl (meth)acrylate, 2-hydroxypropyl (meth)acrylate, 3-hydroxypropyl (meth)acrylate, hydroxycyclohexyl (meth)acrylate, hydroxyphenyl (met)acrylate, diethyleneglycol (meth)acrylate....hydroxyethyl itaconate ([0027]; [0043]; claim 1). Rutter et al. further disclose that the composition comprises acid catalyst which includes free acid and acid generator. Rutter et al. furthermore disclose the composition provides

substantially planarized surface in the manufacture of electronic devices and can function as an antireflective coating for 193 nm radiation when the composition contains aromatic group(abstract; [0062]). Thus, the present claims are anticipated by the disclosure of Rutter et al.

5. Claims 1-13 are rejected under 35 U.S.C. 102(e) as being anticipated by Takei et al. (EP 1 315 045 A1).

Takei et al. disclose a composition for forming a gap-filling material to be used in a semiconductor device by a method of applying the composition to the substrate with holes having an aspect ratio of at least 1 to planarize the surface of the substrate; then applying a resist coating onto a substrate; and finally transferring an image on the substrate using a lithographic process, wherein the composition comprises a polymer having a weight average molecular weight of 500 to 30,000, a crosslinking agent, and additives (page 3, lines 55-56; [0066]-[0069]; claims 1 and 17). Takei et al. further disclose that the polymer is poly(p-vinylphenol), poly(styrene-co-p-vinylphenol), poly(methyl methacrylate-co-p-vinylphenol), poly(2-hydroxyethyl methacrylate-co-p-vinylphenol), poly(butyl acrylate-co-p-vinylphenol), or novolac type phenol resin (Example 6; claims 11 and 13-16). Thus, the present claims are anticipated by the disclosure of Takei et al.

6. Claims 1-2 and 4-13 are rejected under 35 U.S.C. 102(e) as being anticipated by Meador et al. (US 5,919,599).

Meador et al. disclose a deep ultraviolet antireflective composition comprising (A) the reaction product of an acrylic polymer or copolymer and a deep ultraviolet light absorbing carboxylic acid or phenolic dye to produce a polymer or copolymer linked to the carboxylic acid or phenolic dye via a hydroxyester moiety or a hydroxyether moiety respectively, (B) a crosslinking agent, and (C) an acid catalyst (Fig. 1; claim 1). Thus, the present claims are anticipated by the disclosure of Meador et al.

### Response to the Applicants' Arguments

7. Applicant's arguments filed on March 15, 2007 have been fully considered but they are not persuasive.

"EP '045 teaches a gap filling material forming composition containing a hydroxy styrene polymer and a crosslinking agent. The gap filling material is <u>subjected to dry</u> etching by use of a recessed pattern formed by resist coating on the gap filling material.

It is not used in an etching process by an alkaline aqueous solution, as is positively recited, among other features, in independent claim 1. Further, the coated film in EP '045 has a low solubility in alkaline aqueous solution due to the presence of hydroxy styrene polymer and is therefore not suitable to process such as is positively recited in independent claim 1."

Attention is drawn to claim 8 of the present invention, wherein "[t]he gap fill material forming composition according to claim 1, wherein the polymer is a polymer containing hydroxystyrene as repeating unit." Thus, a polymer containing

Application/Control Number: 10/540,389 Page 6

Art Unit: 1713

hydroxystyrene can be used in an etching process by using an alkaline aqueous solution other than in dry etch process disclosed in EP'045. Referring to the property related to the dissolution rate, all references are silent on such property. However, it is an inherent property. If the composition is substantially identical to the one claimed in the present invention, the films made from these substantially identical compositions would possess the identical property such as dissolution rate in the alkaline aqueous solution.

#### Conclusion '

8. **THIS ACTION IS MADE FINAL.** Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the mailing date of this final action.

9. Any inquiry concerning this communication or earlier communications from the

examiner should be directed to Ling-Siu Choi whose telephone number is 571-272-1098.

Page 7

If attempt to reach the examiner by telephone are unsuccessful, the examiner's supervisor, David Wu, can be reach on 571-272-1114.

LING-SUI CHOI PRIMARY EXAMINER

May 31, 2007